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Supplementary Material

Pseudo Voigt fitting model.- Equation 1 explicitly shows all parameters involved; η stablishes the ratio between the Gaussian (left hand summand) and the Lorentzian (right hand summand) contributions to the profile $(0 < \eta < 1)$, λ_0 is the central wavelength of the line, and $\Delta \lambda_G$ and $\Delta \lambda_L$ are the full widths at half maximum (FWHM) of the Gaussian and the Lorentzian contributions, respectively. Since the pseudo-Voigt profile area is normalized to 1 [1], and the studied profiles did not fulfill this condition, a scale factor K accounting for the line intensity was added to the fitting model.

$$I(\lambda) = \left(\frac{2\sqrt{\ln 2}(1-\eta)}{\sqrt{\pi}\Delta\lambda_G}e^{-(\ln 2)\left(\frac{2(\lambda-\lambda_0)}{\Delta\lambda_G}\right)^2} + \frac{\eta\Delta\lambda_L}{2\pi\left[(\lambda-\lambda_0)^2 + \left(\frac{\Delta\lambda_L}{2}\right)^2\right]}\right)K$$

Bibliography

[1] M. Schmid, H. P. Steinrück, and J. M. Gottfried, "A new asymmetric Pseudo-Voigt function for more efficient fitting of XPS lines," *Surf. Interface Anal.*, vol. 46, no. 8, pp. 505–511, 2014.

Equation 1